GAL16LV8

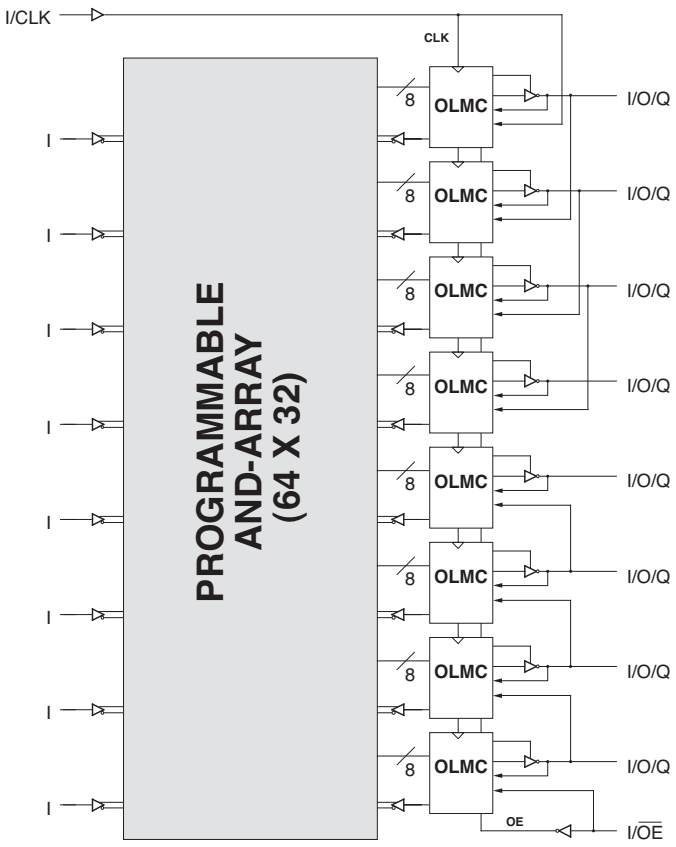
Low Voltage E²CMOS PLD Generic Array Logic™

Lead-Free Package Options Available!

Features

- **HIGH PERFORMANCE E²CMOS® TECHNOLOGY**
  - — 3.5 ns Maximum Propagation Delay
  - — Fmax = 250 MHz
  - — 2.5 ns Maximum from Clock Input to Data Output
  - — UltraMOS® Advanced CMOS Technology
- **3.3V LOW VOLTAGE 16V8 ARCHITECTURE**
  - — JEDEC-Compatible 3.3V Interface Standard
  - — 5V Compatible Inputs
  - — I/O Interfaces with Standard 5V TTL Devices (GAL16LV8C)
- **ACTIVE PULL-UPS ON ALL PINS (GAL16LV8D Only)**
- **E² CELL TECHNOLOGY**
  - — Reconfigurable Logic
  - — Reprogrammable Cells
  - — 100% Tested/100% Yields
  - — High Speed Electrical Erasure (<100ms)
  - — 20 Year Data Retention
- **EIGHT OUTPUT LOGIC MACROCELLS**
  - — Maximum Flexibility for Complex Logic Designs
  - — Programmable Output Polarity
- **PRELOAD AND POWER-ON RESET OF ALL REGISTERS**
  - — 100% Functional Testability
- **APPLICATIONS INCLUDE:**
  - — Glue Logic for 3.3V Systems
  - — DMA Control
  - — State Machine Control
  - — High Speed Graphics Processing
  - — Standard Logic Speed Upgrade
- **ELECTRONIC SIGNATURE FOR IDENTIFICATION**
- **LEAD-FREE PACKAGE OPTIONS**

Functional Block Diagram



Description

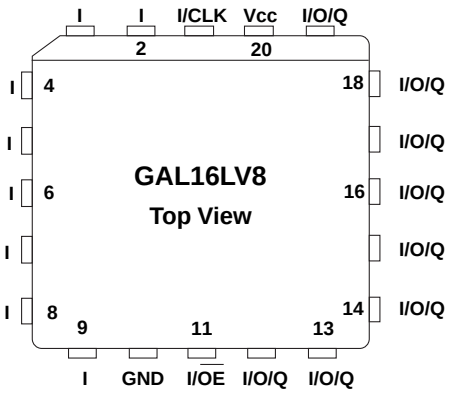
The GAL16LV8D, at 3.5 ns maximum propagation delay time, provides the highest speed performance available in the PLD market. The GAL16LV8C can interface with both 3.3V and 5V signal levels. The GAL16LV8 is manufactured using Lattice Semiconductor's advanced 3.3V E²CMOS process, which combines CMOS with Electrically Erasable (E²) floating gate technology. High speed erase times (<100ms) allow the devices to be reprogrammed quickly and efficiently.

The 3.3V GAL16LV8 uses the same industry standard 16V8 architecture as its 5V counterpart and supports all architectural features such as combinatorial or registered macrocell operations.

Unique test circuitry and reprogrammable cells allow complete AC, DC, and functional testing during manufacture. As a result, Lattice Semiconductor delivers 100% field programmability and functionality of all GAL products. In addition, 100 erase/write cycles and data retention in excess of 20 years are specified.

Pin Configuration

PLCC



Select devices have been discontinued. See Ordering Information section for product status.

Copyright © 2004 Lattice Semiconductor Corp. All brand or product names are trademarks or registered trademarks of their respective holders. The specifications and information herein are subject to change without notice.

GAL16LV8 Ordering Information

Conventional Packaging
Commercial Grade Specifications

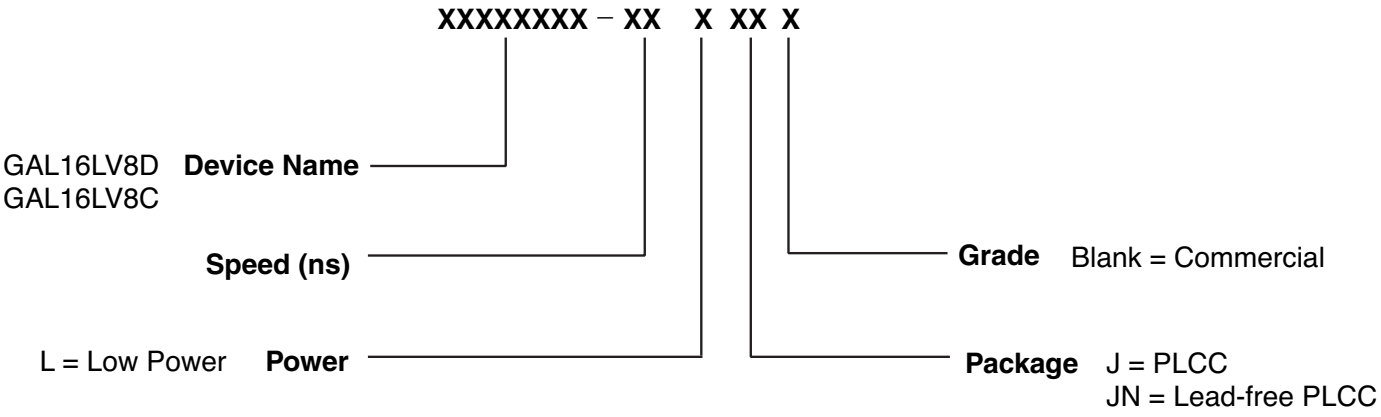
Tpd (ns)	Tsu (ns)	Tco (ns)	Icc (mA)	Ordering #	Package
3.5	3	2.5	70	GAL16LV8D-3LJ	20-Lead PLCC
5	4	3	70	GAL16LV8D-5LJ	20-Lead PLCC
7.5	6	5	65	GAL16LV8C-7LJ[1]	20-Lead PLCC
10	7	7	65	GAL16LV8C-10LJ	20-Lead PLCC
15	12	10	65	GAL16LV8C-15LJ	20-Lead PLCC

Lead-Free Packaging
Commercial Grade Specifications

Tpd (ns)	Tsu (ns)	Tco (ns)	Icc (mA)	Ordering #	Package
3.5	3	2.5	70	GAL16LV8D-3LJN	Lead-Free 20-Lead PLCC
5	4	3	70	GAL16LV8D-5LJN	Lead-Free 20-Lead PLCC
7.5	6	5	65	GAL16LV8C-7LJN[1]	Lead-Free 20-Lead PLCC
10	7	7	65	GAL16LV8C-10LJN	Lead-Free 20-Lead PLCC
15	12	10	65	GAL16LV8C-15LJN	Lead-Free 20-Lead PLCC

1. Discontinued per PCN #06-07. Contact Rochester Electronics for available inventory.

Part Number Description



Select devices have been discontinued. See Ordering Information section for product status.

Output Logic Macrocell (OLMC)

The following discussion pertains to configuring the output logic macrocell. It should be noted that actual implementation is accomplished by development software/hardware and is completely transparent to the user.

There are three global OLMC configuration modes possible: **simple**, **complex**, and **registered**. Details of each of these modes are illustrated in the following pages. Two global bits, SYN and AC0, control the mode configuration for all macrocells. The XOR bit of each macrocell controls the polarity of the output in any of the three modes, while the AC1 bit of each of the macrocells controls the input/output configuration. These two global and 16 individual architecture bits define all possible configurations in a GAL16LV8. The information given on these architecture bits is only to give a better understanding of the device. Compiler software will transparently set these architecture bits from the pin definitions, so the user should not need to directly manipulate these architecture bits.

The following is a list of the PAL architectures that the GAL16LV8 can emulate. It also shows the OLMC mode under which the GAL16LV8 emulates the PAL architecture.

PAL Architectures Emulated by GAL16LV8	GAL16LV8 Global OLMC Mode
16R8	Registered
16R6	Registered
16R4	Registered
16RP8	Registered
16RP6	Registered
16RP4	Registered
16L8	Complex
16H8	Complex
16P8	Complex
10L8	Simple
12L6	Simple
14L4	Simple
16L2	Simple
10H8	Simple
12H6	Simple
14H4	Simple
16H2	Simple
10P8	Simple
12P6	Simple
14P4	Simple
16P2	Simple

Compiler Support for OLMC

Software compilers support the three different global OLMC modes as different device types. These device types are listed in the table below. Most compilers have the ability to automatically select the device type, generally based on the register usage and output enable (OE) usage. Register usage on the device forces the software to choose the registered mode. All combinatorial outputs with OE controlled by the product term will force the software to choose the complex mode. The software will choose the simple mode only when all outputs are dedicated combinatorial without OE control. The different device types listed in the table can be used to override the automatic device selection by the software. For further details, refer to the compiler software manuals.

When using compiler software to configure the device, the user must pay special attention to the following restrictions in each mode. In **registered mode** pin 1 and pin 11 are permanently configured as clock and output enable, respectively. These pins cannot be configured as dedicated inputs in the registered mode.

In **complex mode** pin 1 and pin 11 become dedicated inputs and use the feedback paths of pin 19 and pin 12 respectively. Because of this feedback path usage, pin 19 and pin 12 do not have the feedback option in this mode.

In **simple mode** all feedback paths of the output pins are routed via the adjacent pins. In doing so, the two inner most pins (pins 15 and 16) will not have the feedback option as these pins are always configured as dedicated combinatorial output.

	Registered	Complex	Simple	Auto Mode Select
ABEL	P16V8R	P16V8C	P16V8AS	P16V8
CUPL	G16V8MS	G16V8MA	G16V8AS	G16V8
LOG/iC	GAL16V8_R	GAL16V8_C7	GAL16V8_C8	GAL16V8
OrCAD-PLD	"Registered"[1]	"Complex"[1]	"Simple"[1]	GAL16V8A
PLDesigner	P16V8R[2]	P16V8C[2]	P16V8C[2]	P16V8A
TANGO-PLD	G16V8R	G16V8C	G16V8AS[3]	G16V8

1) Used with **Configuration** keyword.
2) Prior to Version 2.0 support.
3) Supported on Version 1.20 or later.

Select devices have been discontinued.
See Ordering Information section for product status.

Absolute Maximum Ratings(1)

Supply voltage V_{CC} ..... –0.5 to +5.6V
Input voltage applied ..... –0.5 to +5.6V
Off-state output voltage applied ..... –0.5 to +5.6V
Storage Temperature ..... –65 to 150°C
Ambient Temperature with
Power Applied ..... –55 to 125°C

1. Stresses above those listed under the "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress only ratings and functional operation of the device at these or at any other conditions above those indicated in the operational sections of this specification is not implied (while programming, follow the programming specifications).

Recommended Operating Conditions

Commercial Devices:
Ambient Temperature (T_A) ..... 0 to 75°C
Supply voltage (V_{CC})
with Respect to Ground ..... +3.0 to +3.6V

Select devices have been discontinued.
See Ordering Information section for product status.

DC Electrical Characteristics

Over Recommended Operating Conditions (Unless Otherwise Specified)

SYMBOL	PARAMETER	CONDITION	MIN.	TYP.[2]	MAX.	UNITS
V_{IL}	Input Low Voltage		Vss – 0.5	—	0.8	V
V_{IH}	Input High Voltage		2.0	—	5.25	V
I_{IL}	Input or I/O Low Leakage Current	$0V \le V_{IN} \le V_{IL}$ (MAX.)	—	—	-10	µA
I_{IH}	Input or I/O High Leakage Current	$(V_{CC} - 0.2)V \le V_{IN} \le V_{CC}$	—	—	10	µA
		$V_{CC} \le V_{IN} \le 5.25V$	—	—	30	mA
V_{OL}	Output Low Voltage	I_{OL} = MAX. Vin = V_{IL} or V_{IH}	—	—	0.4	V
		I_{OL} = 500 µA Vin = V_{IL} or V_{IH}	—	—	0.2	V
V_{OH}	Output High Voltage	I_{OH} = MAX. Vin = V_{IL} or V_{IH}	2.4	—	—	V
		I_{OH} = -500 µA Vin = V_{IL} or V_{IH}	Vcc-0.45	—	—	V
		I_{OH} = -100 µA Vin = V_{IL} or V_{IH}	Vcc-0.2	—	—	V
I_{OL}	Low Level Output Current		—	—	8	mA
I_{OH}	High Level Output Current		—	—	-4	mA
I_{OS}[1]	Output Short Circuit Current	V_{CC} = 3.3V V_{OUT} = 0.5V T_A = 25°C	-10	—	-60	mA

COMMERCIAL

I_{CC}	Operating Power Supply Current	V_{IL} = 0.0V V_{IH} = 3.0V f_{toggle} = 1MHz Outputs Open	—	45	65	mA

1) One output at a time for a maximum duration of one second. Vout = 0.5V was selected to avoid test problems by tester ground degradation. Characterized but not 100% tested.
2) Typical values are at Vcc = 3.3V and T_A = 25 °C

AC Switching Characteristics

Over Recommended Operating Conditions (Unless Otherwise Specified)

PARAMETER	TEST COND[1].	DESCRIPTION	COM -7 MIN.	COM -7 MAX.	COM -10 MIN.	COM -10 MAX.	COM -15 MIN.	COM -15 MAX.	UNITS
tpd[2]	A	Input or I/O to Combinational Output	1	7.5	1	10	1	15	ns
tco[2]	A	Clock to Output Delay	1	5	1	7	1	10	ns
tcf[3]	—	Clock to Feedback Delay	—	4	—	5	—	8	ns
tsu	—	Setup Time, Input or Feedback before Clock↑	6	—	7	—	12	—	ns
th	—	Hold Time, Input or Feedback after Clock↑	0	—	0	—	0	—	ns
fmax[4]	A	Maximum Clock Frequency with External Feedback, 1/(tsu + tco)	90.9	—	71.4	—	45.5	—	MHz
	A	Maximum Clock Frequency with Internal Feedback, 1/(tsu + tcf)	100	—	83.3	—	50	—	MHz
	A	Maximum Clock Frequency with No Feedback	100	—	83.3	—	62.5	—	MHz
twh	—	Clock Pulse Duration, High	5	—	6	—	8	—	ns
twl	—	Clock Pulse Duration, Low	5	—	6	—	8	—	ns
ten	B	Input or I/O to Output Enabled	—	9	—	10	—	15	ns
	B	$\overline{OE}$ to Output Enabled	—	6	—	8	—	15	ns
tdis	C	Input or I/O to Output Disabled	—	9	—	10	—	15	ns
	C	$\overline{OE}$ to Output Disabled	—	6	—	8	—	15	ns

1) Refer to **Switching Test Conditions** section.
2) Minimum values for **t**pd and **t**co are not 100% tested but established by characterization.
3) Calculated from **f**max with internal feedback. Refer to **fmax Descriptions** section.
4) Refer to **fmax Descriptions** section. Characterized but not 100% tested.

Capacitance (T_A = 25°C, f = 1.0 MHz)

SYMBOL	PARAMETER	TYPICAL	UNITS	TEST CONDITIONS
C_I	Input Capacitance	8	pF	V_{CC} = 3.3V, V_I = 0V
$C_{I/O}$	I/O Capacitance	8	pF	V_{CC} = 3.3V, $V_{I/O}$ = 0V

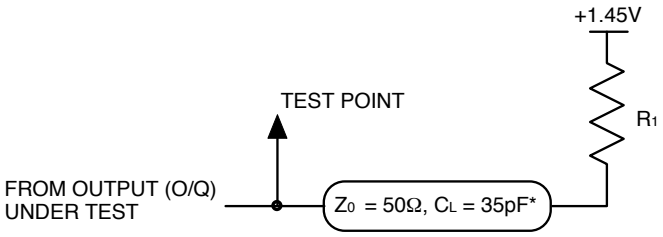
Select devices have been discontinued.
See Ordering Information section for product status.

GAL16LV8D: Switching Test Conditions

Input Pulse Levels	GND to 3.0V
Input Rise and Fall Times	1.5ns 10% – 90%
Input Timing Reference Levels	1.5V
Output Timing Reference Levels	1.5V
Output Load	See Figure

GAL16LV8D Output Load Conditions (see figure)

Test Condition		R_1	C_L
A		50Ω	35pF
B	High Z to Active High at 1.9V	50Ω	35pF
	High Z to Active Low at 1.0V	50Ω	35pF
C	Active High to High Z at 1.9V	50Ω	35pF
	Active Low to High Z at 1.0V	50Ω	35pF



*C_L INCLUDES TEST FIXTURE AND PROBE CAPACITANCE

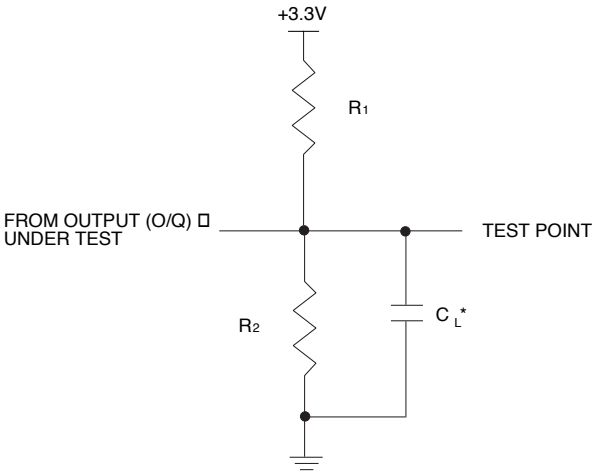
GAL16LV8C: Switching Test Conditions

Input Pulse Levels	GND to 3.0V
Input Rise and Fall Times	1.5ns 10% – 90%
Input Timing Reference Levels	1.5V
Output Timing Reference Levels	1.5V
Output Load	See Figure

3-state levels are measured 0.5V from steady-state active level.

GAL16LV8C Output Load Conditions (see figure)

Test Condition		R_1	R_2	C_L
A		316Ω	348Ω	35pF
B	Active High	316Ω	348Ω	35pF
	Active Low	316Ω	348Ω	35pF
C	Active High	316Ω	348Ω	5pF
	Active Low	316Ω	348Ω	5pF



*C_L INCLUDES TEST FIXTURE AND PROBE CAPACITANCE

Select devices have been discontinued.
See Ordering Information section for product status.